SCLS116C - DECEMBER 1982 - REVISED MAY 1997

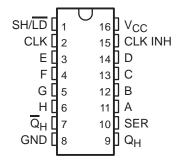
- Complementary Outputs
- Direct Overriding Load (Data) Inputs
- Gated Clock Inputs
- Parallel-to-Serial Data Conversion
- Package Options Include Plastic Small-Outline (D), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

#### description

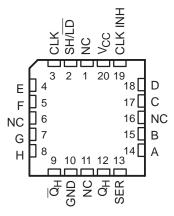
The 'HC165 are 8-bit parallel-load shift registers that, when clocked, shift the data toward a serial ( $Q_H$ ) output. Parallel-in access to each stage is provided by eight individual direct data (A–H) inputs that are enabled by a low level at the shift/load (SH/ $\overline{LD}$ ) input. The 'HC165 also feature a clock-inhibit (CLK INH) function and a complementary serial ( $\overline{Q}_H$ ) output.

Clocking is accomplished by a low-to-high transition of the clock (CLK) input while SH/LD is held high and CLK INH is held low. The functions of CLK and CLK INH are interchangeable. Since a low CLK and a low-to-high transition of CLK INH also accomplish clocking, CLK INH should be changed to the high level only while CLK is high. Parallel loading is inhibited when SH/LD is held high. While SH/LD is low, the parallel inputs to the register are enabled independently of the levels of the CLK, CLK INH, or serial (SER) inputs.

SN54HC165 . . . J OR W PACKAGE SN74HC165 . . . D, N, OR PW PACKAGE (TOP VIEW)



# SN54HC165 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

The SN54HC165 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC165 is characterized for operation from –40°C to 85°C.

#### **FUNCTION TABLE**

	INPUT	S	FUNCTION
SH/LD	CLK	CLK INH	FUNCTION
L	Χ	Х	Parallel load
Н	Н	Χ	No change
Н	Χ	Н	No change
Н	L	1	Shift <sup>†</sup>
Н	$\uparrow$	L	Shift <sup>†</sup>

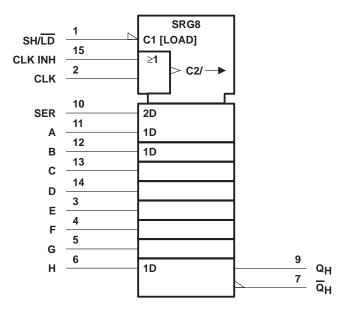
<sup>†</sup> Shift = content of each internal register shifts toward serial output Q<sub>H</sub>. Data at SER is shifted into the first register.



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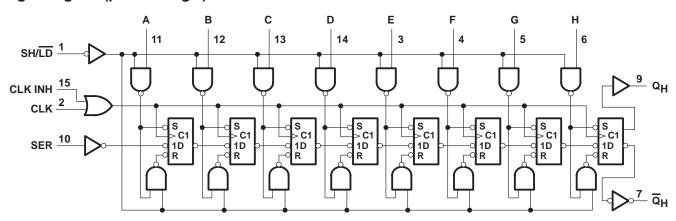


#### logic symbol<sup>†</sup>



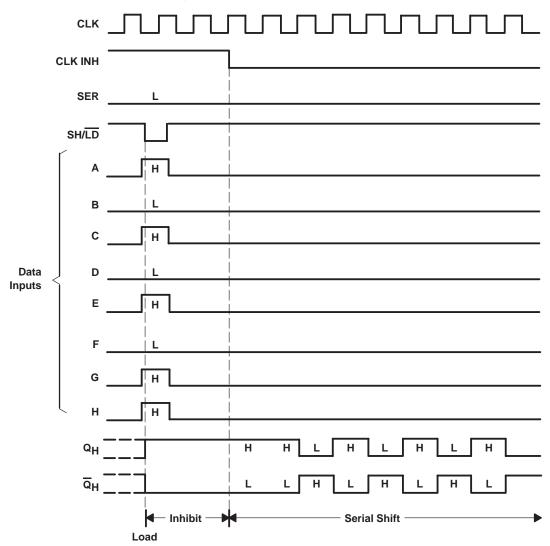
<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, PW, and W packages.

### logic diagram (positive logic)



Pin numbers shown are for the D, J, N, PW, and W packages.

#### typical shift, load, and inhibit sequence



#### absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V <sub>CC</sub>		
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (s	ee Note 1)	±20 mA
Output clamp current, IOK (VO < 0 or VO > VC	C) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )		±25 mA
Continuous current through V <sub>CC</sub> or GND		±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2)	: D package	113°C/W
	-	78°C/W
	PW package	149°C/W
Storage temperature range, T <sub>stg</sub>		–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



### SN54HC165, SN74HC165 8-BIT PARALLEL-LOAD SHIFT REGISTERS

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#### recommended operating conditions

			SI	SN54HC165		18	174HC16	55	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vсс	Supply voltage		2	5	6	2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			1.5			
ViH	/IH High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V
		V <sub>CC</sub> = 6 V	4.2			4.2			
VIL	Low-level input voltage	V <sub>CC</sub> = 2 V	0		0.5	0		0.5	V
		V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	
		V <sub>CC</sub> = 6 V	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		V <sub>CC</sub> = 2 V	0		1000	0		1000	
t <sub>t</sub> †	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V	0		500	0		500	ns
		V <sub>CC</sub> = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C

<sup>†</sup> If this device is used in the threshold region (from V<sub>IL</sub>max = 0.5 V to V<sub>IH</sub>min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t<sub>t</sub> = 1000 ns and V<sub>CC</sub> = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	Т	A = 25°C	;	SN54HC165		SN74HC165		UNIT
PARAMETER			TIONS VCC		TYP	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I <sub>OL</sub> = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
	$I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.4		0.33		
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
ICC	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

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# timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			V	T <sub>A</sub> = 2	25°C	SN54F	IC165	SN74F	IC165	UNIT
			VCC	MIN	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	0	6	0	4.2	0	5	
fclock	Clock frequency		4.5 V	0	31	0	21	0	25	MHz
			6 V	0	36	0	25	0	29	
			2 V	80		120		100		
		SH/LD low	4.5 V	16		24		20		
١.	Pulse duration		6 V	14		20		17		ns
t <sub>w</sub>	Puise duration		2 V	80		120		100		115
		CLK high or low	4.5 V	16		24		20		
			6 V	14		20		17		
			2 V	80		120		100		
		SH/LD high before CLK↑	4.5 V	16		24		20		
		6 V	14		20		17			
			2 V	40		60		50		
	SER before CLK↑	4.5 V	8		12		10			
			6 V	7		10		9		ns
			2 V	100		150		125		
t <sub>su</sub>	Setup time	CLK INH low before CLK↑	4.5 V	20		30		25		
			6 V	17		25		21		
			2 V	40		60		50		
		CLK INH high before CLK↑	4.5 V	8		12		10		
			6 V	7		10		9		
			2 V	100		150		125		
		Data before SH/LD↓	4.5 V	20		30		25		
			6 V	17		26		21		
			2 V	5		5		5		
		SER data after CLK↑	4.5 V	5		5		5		
<b> </b>	Hold time		6 V	5		5		5		no
th	HOID LITTIE		2 V	5		5		5		ns
		PAR data after SH/LD↓	4.5 V	5		5		5		
			6 V	5		5		5		

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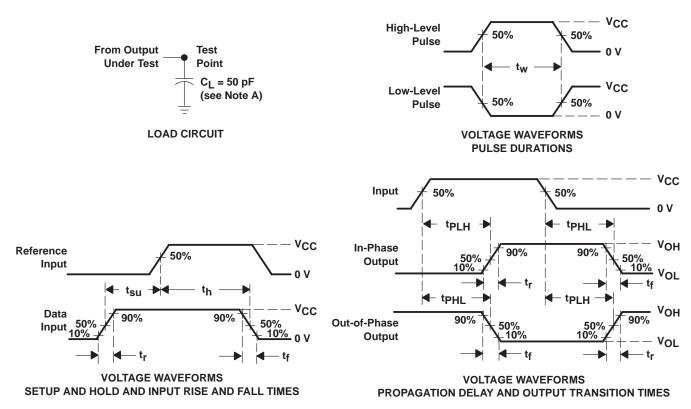
# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	Δ = 25°C	;	SN54F	IC165	SN74H	IC165	UNIT
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	6	13		4.2		5		
fmax			4.5 V	31	50		21		25		MHz
			6 V	36	62		25		29		
			2 V		80	150		225		190	
	SH/LD	Q <sub>H</sub> or $\overline{Q}_{H}$	4.5 V		20	30		45		38	1 1
			6 V		16	26		38		32	
	CLK	Q <sub>H</sub> or $\overline{Q}_{H}$	2 V		75	150		225		190	ns
<sup>t</sup> pd			4.5 V		15	30		45		38	
			6 V		13	26		38		32	
	Н	H $Q_H$ or $\overline{Q}_H$	2 V		75	150		225		190	
н			4.5 V		15	30		45		38	
			6 V		13	26		38		32	
			2 V		38	75		110		95	
t <sub>t</sub>		Any	4.5 V		8	15		22		19	ns
			6 V		6	13		19		16	

## operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance	No load	75	pF

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 6 \ ns$ ,  $t_f = 6 \ ns$ .
- C. For clock inputs,  $f_{\mbox{max}}$  is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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